

Application/Control No.	Applicant(s)/Patent under Reexamination
10/708,765	CHAN ET AL.
Examiner	Art Unit
Tyrone W. Smith	2837

SEARCHED					
Class	Subclass	Date	Examiner		
318	138 439 254 700 685 696	·8/11/2005	TS		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NO (INCLUDING SEARC		)
	DATE	EXMR
United States Patent Database Derwent Japanese European Non-Patent Literature	8/11/2005	TS
East Search (see attached)	8/11/2005	TS
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